

Notice of References Cited		Application/Control No. 09/872,647	Applicant(s)/Patent Under Reexamination SRIVASTAVA ET AL.	
		Examiner Satish S. Rampuria	Art Unit 2191	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,339,776 B1	01-2002	Dayani-Fard et al.	707/102
*	B	US-6,748,583 B2	06-2004	Aizenbud-Reshef et al.	717/127
*	C	US-6,802,054 B2	10-2004	Faraj, Mazen	717/128
*	D	US-6,944,797 B1	09-2005	Guthrie et al.	714/45
*	E	US-7,165,190 B1	01-2007	Srivastava et al.	714/38
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	A tool for testing hypermedia systems, Leung, H.K.N.; EUROMICRO Conference, 1999. Proceedings. 25 th Volume 2, 8-10 Sept. 1999, IEEE, Page(s):202 - 209 vol.2
	V	Reverse mapping of referral links from storage hierarchy for Web documents, Chen Ding; Chi-Hung Chi; Tam, V.; Tools with Artificial Intelligence, 2000. ICTAI 2000. Proceedings. 12th IEEE International Conference on, 13-15 Nov. 2000, IEEE, Page(s):216 - 219
	W	Using technology to tailor electronic information to users, Surray, A.; Lavoie, R.; Professional Communication Conference, 1996. IPCC '96 Proceedings. 'Communication on the Fast Track', International, 18-20 Sept. 1996, IEEE, Page(s):209 - 214
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Correction

Notice of References Cited	Application/Control No. 09/872,647	Applicant(s)/Patent Under Reexamination SRIVASTAVA ET AL.	
	Examiner Satish S. Rampuria	Art Unit 2124	Page 1 of 2

U.S. PATENT DOCUMENTS

* 	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,708,173 B1	03-2004	Behr et al.	707/10
B	US-5,708,825	01-1998	Sotomayor, Bernardo Rafael	715/501.1
C	US-6,738,778 B1	05-2004	Williamson et al.	707/101
D	US-6,282,701 B1	08-2001	Wygodny et al.	717/125
E	US-2002/0107882 A1	08-2002	Gorelick et al.	707/500.1
F	US-2002/0004803	01-2002	Serebrennikov, Oleg	707/513
G	US-2002/0066081 A1	05-2002	Duesterwald et al.	717/128
H	US-6,738,965 B1	05-2004	Webster, Matthew Alexander	717/128
I	US-5,920,719 A	07-1999	Sutton et al.	717/130
J	US-6,715,140 B1	03-2004	Haga, Yutaka	717/130
K	US-6,574,792 B1	06-2003	Easton, John Paul	717/142
L	US-6,353,924 B1	03-2002	Ayers et al.	717/128
M	US-2002/0095660 A1	07-2002	O'Brien et al.	717/127

FOREIGN PATENT DOCUMENTS

* 	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

* 	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
U	Helmbold et al., Detecting data races from sequential traces, 1991, IEEE, pg. 408-417	
V	Tolujev et al., Assessment of simulation models based on traces-file analysis: A metamodeling approach, 1998, IEEE, vol. 1, pg. 443-450	
W	Helmbold et al., Determining possible event orders by analysing sequential traces, IEEE, vol. 4, pg. 827-840, 1993	
X	Palnitkar et al., Finite state machine trace analysis program, 1994, IEEE, pg. 52-57	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.